



**RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2878**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

SAITO et al.

Art Unit: 2138

Application No.: 10/763,334

Examiner: P. Chung

Filed: January 26, 2004

Attorney Dkt. No.: 107337-00056

For: SEMICONDUCTOR TESTING CIRCUIT, SEMICONDUCTOR STORAGE DEVICE, AND SEMICONDUCTOR TESTING METHOD

AMENDMENT UNDER 37 C.F.R. § 1.116

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

January 5, 2007

Sir:

In response to the Office Action mailed October 5, 2006, entry of the following amendment and consideration of the following remarks are respectfully requested.

Claim Amendments begin on page 2 of this paper.

Remarks begin on page 8 of this paper.